

Notic of Referenc s Cited	Application/Control No. 09/406,663	Applicant(s)/Patent Under Reexamination KNEBEL ET AL.	
	Examiner Fred Ferris	Art Unit 2123	Page 1 of 2

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,483,327 ✓	11-2002	Bruce et al.	324/752
	C	US-5,251,159 ✓	10-1993	Rowson, James A.	703/14
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	E	US-5,270,643 ✓	12-1993	Richardson et al.	324/751
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission", D. Knebel et al, International Test Conference, IEEE, August 1998 ✓
	V	"Failure Analysis of ULSI circuits Using Photon Emission", Y. Uraoka, IEEE Log Number 9211664, IEEE 1993 ✓
	W	"The Attack of the "Holey Shmoos": A Case Study of Advanced DFD and Picosecond Imaging Circuit Analysis (PICA)", W. Huott, ITC International Test Conference, IEEE, January 1999 ✓
	X	"An Integrated Photon Emission Microscope and MOSFET Caharterization System of Combinerd Microscopic and Macroscopic Device Analysis", T.H. Ng, IEEE Proceedings fo 7 th IPFA '99, August 1999 ✓

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Fred Ferris	Art Unit 2123	Page 2 of 2

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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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